# **LS7060/7062**

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# 32 BIT/DUAL 16 BIT BINARY UP COUNTER WITH BYTE MULTIPLEXED THREE-STATE OUTPUTS

### FEATURES:

- DC to 15 MHz Count Frequency
- Byte Multiplexer
- DC to 1 MHz Scan Frequency
- +4.75V to +5.25V Operation (VDD-Vss)
- Three-State Data Outputs, Bus and TTL Compatible
- Inputs TTL and CMOS Compatible
- Unique Cascade Feature Allows Multiplexing of Successive Bytes of Data in Sequence in Multiple Counter Systems
- Low Power Dissipation
- 18 Pin DIP or 18 Pin SOIC See Figures 1 & 2

### **DESCRIPTION:**

The LS7060/LS7062 is a monolithic, ion implanted MOS Silicon Gate, 32 bit/dual 16 bit up counter. The IC includes latches, multiplexer, eight three-state binary data output drivers and output cascading logic.

### **DESCRIPTION OF OPERATION:**

### 32 (16) BIT BINARY UP COUNTER - LS7060 (LS7062)

The 32(16) bit static ripple through counter increments on the negative edge of the input count pulse. Maximum ripple time is  $4\mu$ s (2 $\mu$ s) - transition count of 32(16) ones to 32(16) zeros. Guaranteed count frequency is DC to 15MHz. See Figure 9A(9B) for Block Diagram.

### COUNT, ALT COUNT (LS7060)

Input count pulses to the 32 bit <u>counter may</u> be applied through either of these two inputs. The ALT COUNT input circuitry contains a Schmitt trigger network which allows proper counting with "infinitely" long clock edges. A high applied to either of these two inputs inhibits counting.

### COUNT A, ALT COUNT A (LS7062)

Input count pulses to the first 16 bit counter may be applied through either of these two inputs. The ALT COUNT A input circuitry contains a Schmitt trigger network which allows proper counting with "infinitely" long clock edges. A high applied to either of these two inputs inhibits counting.

### RESET

All 32 counter bits are reset to zero when  $\overrightarrow{\text{RESET}}$  is brought low for a minimum of 1µs.  $\overrightarrow{\text{RESET}}$  must be high for a minimum of 300ns before next valid count can be recorded.

### TEST COUNT (LS7060)

Count pulses may be applied to the last 16 bits of the binary counter through this input, as long as Bit 16 of the counter is a low. The counter advances on the negative transition of these pulses. This input is intended to be used for test purposes.

### VDD(+V) 18 COUNT 1 Ľ 17 B4 OUT ALT COUNT 2 16 B5 OUT B3 OUT 3 15 B6 OUT B2 OUT 4 LS7060 14 B7 OUT B1 OUT 5 13 TEST COUNT B0 OUT 6 SCAN RESET/LOAD RESET 7 12 CASCADE EN OUT 8 ENABLE 11 10 SCAN Vss (-V) 9 FIGURE 1



### COUNT B (LS7062)

Count pulses may be applied to the last 16 bits of the binary counter through this input. The counter advances on the negative transition of these pulses.

### LATCHES - LS7060 (LS7062)

32 bits of latch are provided for storage of counter data. All latches are loaded when the LOAD input is brought low for a minimum of 1µs and kept low until a minimum of 4µs (2µs) has elapsed from previous negative edge of count pulse (ripple time). Storage of valid data occurs when LOAD is brought high for a minimum of 250ns before next negative edge of count pulse or RESET.

### **PIN ASSIGNMENT - TOP VIEW**

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### SCAN COUNTER AND DECODER

The scan counter is reset to the least significant byte position (State 1) when SCAN RESET input is brought low for a minimum of 1µs. The scan counter is enabled for counting as long as the ENABLE input is held low. The counter advances to the next significant byte position on each negative transition of the SCAN pulse. When the scan counter advances to State 5 it disables the Output Drivers and stops in that state until SCAN RESET is again brought low.

### SCAN

When the scan counter is enabled, each negative transition of this input advances the scan counter to its next state. When SCAN is low the Data Outputs are disabled. When SCAN is brought high the Data Outputs are enabled and present the latched counter data corresponding to the present state of the scan counter. Therefore, in microprocessor applications, the Data Output Bus may be utilized for other activities while new data is propagating to the outputs. This positive SCAN pulse can be viewed as a "Place the next byte on my bus" instruction from the microprocessor. Minimum positive and negative pulse widths of 500ns for the SCAN signal are required for scan counter operation.

### SCAN RESET/LOAD

When this input is brought low for a minimum of  $1\mu$ s, the scan counter is reset to State 1, the least significant byte position, and the latches are simultaneously loaded with new count information.

### ENABLE

When this input is high, the scan counter and the Data Outputs are disabled. When ENABLE is low, the scan counter and Data Outputs are enabled for normal operation. Transition of this input should only be made while the SCAN input is in a low state in order to prevent false clocking of the scan counter.

### **CASCADE ENABLE**

This output is normally high. It transitions low and stays low when the scan counter advances to <u>State 5</u>. In a multiple counter system this output is connected to the <u>ENABLE</u> input of the next counter in the cascade string. The SCAN input and SCAN RESET/LOAD input are carried to all the counters in the "Cascade". Counter 1 then presents its bytes of data to the Output Bus on each positive transition of the SCAN pulse as previously discussed. When State 5 of Counter 1 is achieved, Counter 2 presents its data to the Output Bus. This sequence continues until all counters in the cascade have been addressed. See Figure 5 for an illustration of a 3 device cascade design. This output is TTL and CMOS compatible.

### THREE-STATE DATA OUTPUT DRIVERS

The eight Data Output Drivers are disabled when either ENABLE input is high, the scan counter is in State 5, or the SCAN input is low. The Output Drivers are TTL and Bus compatible.

The information included herein is believed to be accurate and reliable. However, LSI Computer Systems, Inc. assumes no responsibilities for inaccuracies, nor for any infringements of patent rights of others which may result from its use.

ABSOLUTE MAXIMUM RATINGS:			
PARAMETER	SYMBOL	VALUE	UNIT
StorageTemperature	Тѕтд	-55 to +150	°C
Operating Temperature	ТА	0 to +70	°C
Voltage (any pin to Vss)	Vin	+10 to -0.3	V

### DC ELECTRICAL CHARACTERISTICS:

 $(VDD = +5V \pm 5\%, VSS = 0V, TA = 0^{\circ}C \text{ to } + 70^{\circ}C \text{ unless otherwise noted.})$ 

PARAMETER Power Supply Current	SYMBOL Idd	Min -	<b>MAX</b> 15	<b>UNIT</b> mA	CONDITIONS At Maximum Operating Frequency VDD = Max, Outputs No Load
Input High Voltage	Vін	+3.5	Vdd	V	-
Input Low Voltage	VIL	0	+0.6	V	-
Output High Voltage					
CASCADE ENABLE	Vон	Vdd-0.2	-	V	IO = 0, $VDD = Min$
		+2.4	-	V	Io = -100µA, Vdd = Min
B0 - B7		+2.4	-	V	Io = -260µA, Vdd = Min
Output Low Voltage		+2.0	-	V	$IO = 750\mu A$ , VDD = Min
CASCADE ENABLE	Vol	-	+0.2	V	IO = 0, $VDD = Min$
			+0.4	V	IO = 1.6mA, $VDD = Min$
B0 - B7			+0.4	V	IO = 1.6 mA, $VDD = Min$
Output Source Current	Isource	3.0	-	mA	VO = +1.2V, $VDD = Min$
B0 - B7 Outputs		4.8	-	mA	VO = +0.8V, $VDD = Min$
-		7.3	-	mA	VO = +0.4V, $VDD = Min$
Output Sink Current	Isink	5.7	-	mA	VO = +1.2V, $VDD = Min$
B0 - B7 Outputs		4.0	-	mA	VO = +0.8V, $VDD = Min$
-		2.2	-	mA	VO = +0.4V, $VDD = Min$
Output Leakage Current B0 - B7 (Off State)	IOL	-	1	μA	VO = +.4V to $+2.4V,VDD = Min$
Input Capacitance	CIN	-	6	pF	TA = 25°C, f = 1MHz
Output Capacitance	COUT	-	12	pF	TA = 25°C, f = 1MHz
Input Leakage Curr <u>ent</u> ENABLE, RESET, SCAN	ILI	-	1	μA	VDD = Max

INPUT CURRENT					
*SCAN RESET/LOAD	Ін	-	-2.5	μA	VDD = Max, VIH = +3.5
	lı∟	-	-5	μA	VDD = Max, VIL = 0
**All Count inputs	Ін	-	5	μA	VDD = Max, VIH = +3.5
	lı∟	-	1	μA	VDD = Max, VIL = 0

\*Input has internal pull-up resistor to VDD \*\* Inputs have internal pull-down resistor to Vss

## DYNAMIC ELECTRICAL CHARACTERISTICS:

(VDD = +5V  $\pm$  5%, VSS = 0V, TA = 0°C to +70°C unless otherwise noted.)

PARAMETER Count Frequency (All Count inputs)	SYMBOL fc	MIN DC	<b>MAX</b> 15	<b>UNIT</b> MHz	CONDITIONS
Count Pulse Width (All Count Inputs)	tCPW	30	-	ns	Measured at 50% point, Max tr, tr = 10ns
Count Rise & Fall time (Pins 1, 13)	tr, tf	-	30	μs	-
Count Ripple Time (Pins 1, 2 - LS7062)	tCR	-	4	μs	Transition from 32 ones to 32 zeros from negative edge of count pulse
Count Ripple Time (Pin 13 - LS7060) (Pins 1,2,13 - LS7062)	tCR	-	2	μs	Transition of 16 bits from all ones to all zeros from negative edge of count pulse
(All Counter Stages Fully Reset)	tRPW	500	-	ns	Measured at 50% point Max tr, tr = 200ns
RESET Removal Time (Reset Removed From All Counter Stages)	tRR	-	250	ns	Measured from $\overline{RESET}$ signal at VIH
SCAN Frequency	fsc	-	1	MHz	
SCAN Pulse Wildth	tSCPW	500	-	ns	Measured at 50% point
SCAN RESET/LOAD Pulse Width (All latches loaded and Scan Counter Reset to Least Significant Byte)	trscpw	1	-	μs	Max tr, tf = 100ns Measured at 50% point Max tr, tf = 200ns
SCAN RESET/LOAD Removal Time (Reset Removed from Scan Counter; Load Command Removed From Latches)	trscr	-	250	ns	Measured from SCAN RESET/ LOAD at Viн
Output Disable Delay Time (B0 - B7)	tDOD	-	200	ns	Transition to Output High Impedance State Measured <u>From Sc</u> an at Vı∟ or ENABLE at Vıн
Output ENABLE Delay Time (B0 - B7)	tDOE	-	200	ns	Transition to Valid On State Measured from Scan at VIH and ENABLE at VIL; Delay to Valid Data Levels for CoL =10pF and one TTL Load or Valid Data Currents for High Capacitance Loads
O <u>utput Delay Time</u> CASCADE ENABLE	tDCE	-	300	ns	Negative Transition from Scan at VL and ST5 of Scan <u>Counter or Positive</u> Transition From SCAN RESET/LOAD at VIL to Valid Data Levels for CoL = 10pF and one TTL Load











FIGURE 5. ILLUSTRATION OF A 3 DEVICE CASCADE









FIGURE 8. SYNCHRONIZING INHIBIT WITH COUNT PULSES FOR COUNTER A FOR LS7062



